Search Notes



Applicati	on/Control No.	Applicant(s)/Patent Under Reexamination
10599310)	VOLOSHIN ET AL.
Examine	r	Art Unit
Young J I	Kim	1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES				
Search Notes	Date	Examiner		
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) - see enclosed for text search strategy	9/29/2010	/YJK/		
STN commercial Databases (Biosis, Medline, Embase, Embal, CAPlus) - see enclosed for text search strategy	9/29/2010	/YJK/		
STN search updated - see enclosed	4/28/2011	/YJK/		
Patent Databases - updated - see enclosed	4/28/2011	/YJK/		

INTERFERENCE SEARCH			
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/Young J Kim/ Primary Examiner.Art Unit 1637

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